

Chalmers Advanced TEM/STEM School: 19-21 November, 2018

Programme

Monday, 19 November

12.00 - 13.00	Registration (PJ Lecture Hall)
13.00 - 14.15	Lecture #1: Imaging in the TEM and STEM
14.15 - 14:45	Special Lecture #1: Applications of TEM and STEM for photovoltaic materials and devices (Wolfgang Jäger)
14.45 - 15.15	Special Lecture #2: Electron holography (Martha R. McCartney)
15.15 - 15.45	Break
15.45 - 16.30	Special Lecture #3: Limits to quantification in the TEM and STEM (Andy Yankovich)
16.30 - 16.45	Introduction to Chalmers Materials Analysis Laboratory
16.45 - 18.00	Laboratory Tour (4 groups)
18.15	DINNER - <i>h</i> Room

Tuesday, 20 November (Kollektorn Lecture Hall)

09.00 - 10.15	Lecture #2: Approaches to microanalysis – EELS and EDX
10.15 - 10.30	Break
10.30 - 11.15	Special Lecture #4: Cutting-edge applications of aberration-corrected TEM/STEM (Eiji Okunishi)
11.15 - 12.45	Laboratory sessions (3 in parallel)
12.45 - 13.00	School photo
13.00 - 13.45	LUNCH – Café Canyon
13.45 - 15.00	Lecture #3: High-resolution imaging – theory and practice
15.00 - 15.15	Break
15.15 - 16.00	Special Lecture #5: <i>In situ</i> TEM (Ludvig de Knoop)
16.00 - 17.30	Laboratory sessions (3 in parallel)
18.00	DINNER (Sponsored by JEOL) – <i>h</i> Room

Wednesday, 21 November (PJ Lecture Hall)

09.00 - 10.15	Lecture #4: Approaches to aberration correction
10.15 - 11.00	Special Lecture #6: Exploring resolution limits in the electron microscope (David J. Smith)
11.00 - 11.15	Break
11.15 - 12.45	Laboratory sessions (3 in parallel)
	Departure

Laboratory sessions (90 minutes each)

ARM – Monochromators (Eiji Okunishi, Masaki Mukai)

Tecnai – *In situ* TEM (Ludvig de Knoop)

Titan – Acquisition and processing of atomic-resolution STEM images (Andrew Yankovich)